Search Notes

Application/Control No.	Applicant(s)/Patent unde Reexamination	r
09/764,778	SIREAU, JEAN-YVES	
Examiner	Art Unit	
JAGDISH PATEL	3624	

SEARCHED				
Class	Subclass	Date	Examiner	
705	37	3/30/2006	gnl	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST (Patent Databases, US & Foreign)	3/30/2006	gul		
Dialog NPL (Business Databases)	3/30/2006	and		